



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Frum et al.	Group Art Unit: N/A
Application No: 10/615,159	Examiner: Unknown
Confirmation No: Unknown	Attorney Docket No:
Filed: 07/07/2003	007352 USA/ETCH/DRIE/JB
Title: INTERFEROMETRIC ENDPOINT DETECTION IN A SUBSTRATE ETCHING PROCESS	March 29 2004 San Francisco, California

INFORMATION DISCLOSURE STATEMENT

Mail Stop Non-Fee Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir/Madam:

Attached hereto is a PTO-1449 form listing documents believed relevant to the subject application. It is respectfully requested that these documents be considered by the Examiner and an initialed copy of the form be returned to the undersigned.

Applicant believes that the Office should consider this Information Disclosure Statement because it is being filed before the mailing of a first Office Action on the merits.

It is believed that no fee is due for the filing of this Information Disclosure Statement. However, if any fee is due, the Commissioner is hereby authorized to charge payment of any such fees to Deposit Account No. 10-0258.

Also, if any Petition is required for the filing of this Information Disclosure Statement, such Petition is requested herein.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage in an envelope addressed to:

Mail Stop Non-Fee Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

By: J. Taylor Branche
J. Taylor Branche

Date of Deposit: March 29, 2004

It is believed that this disclosure complies with the requirements of 37 C.F.R. §§ 1.56, 1.97, and 1.98, and the Manual of Patent Examining Procedures § 707.05(b). If for some reason the Examiner considers otherwise, it is respectfully requested that the undersigned be called so that any deficiencies can be remedied.

It should be noted that the word "prior" has been deleted from the attached PTO-1449 form(s).

A copy of each foreign patent document and relevant art (not including US Patents and application publications) is enclosed.

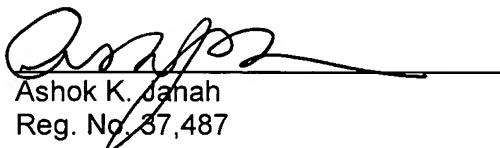
Some of the documents have markings thereon. No significance is meant to be attached to the markings.

With regard to any translations which may be provided here
These documents are not necessarily analogous.

Respectfully submitted,
JANAH & ASSOCIATES, P.C.

Date: March 29, 2004

By:



Ashok K. Janah
Reg. No. 37,487

Please direct all telephone calls to:

Ashok K. Janah
(415) 538-1555

Please continue to send all correspondence to:

Applied Materials, Inc.
Patent Department, M/S 2061
P.O. Box 450A
Santa Clara, California 95052

Encl.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION		DOCKET NO: 007352 USA/ETCH/DRIE/JB							APPLICATION NO.: 10/615,159				
		APPLICANT: Frum et al.											
		FILING DATE: 7/7/2003							GROUP ART UNIT: 1763				
U.S. PATENT DOCUMENTS													
EXAMINER INITIAL	DOCUMENT NUMBER							DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE	
	3	6	1	2	6	9	2	10/12/1971	Kruppa, et al.				
	3	8	2	4	0	1	7	04/01/1975	Galyon				
	3	8	7	4	7	9	7	04/01/1975	Kasai				
	3	9	8	5	4	4	7	10/12/1976	Kruppa, et al.				
	4	1	4	1	7	8	0	02/27/1979	Kleinknecht, et al.				
	4	1	9	8	2	6	1	04/15/1980	Busta, et al.				
	4	2	0	8	2	4	0	06/17/1980	Latos				
	4	3	1	7	6	9	8	03/02/1982	Christol, et al.				
	4	3	2	8	0	6	8	05/04/1982	Curtis				
	4	3	6	7	0	4	4	01/04/1983	Booth, Jr, et al				
FOREIGN PATENT DOCUMENTS													
	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
												YES	NO
	0	5	1	1	4	4	8	11/4/1992	EP Application				
	0	7	5	3	9	1	2	01/15/1997	EP Application				
	2	2	9	3	7	9	5	04/10/1996	Great Britain				
	0	7	0	9	8	7	7	05/01/1996	EP Application			X	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)													
	PCT International Search Report dated September 2, 1999												
	European Search Report dated September 4, 2001, P.B. 5818- Patentlaan 2, 2280 HV Rijswijk (ZH), The Hague												
EXAMINER										DATE CONSIDERED			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.													

